

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	1	("20040129220").PN.	US-PGPU B	OR	OFF	2005/09/27 13:35
S2	1	S1 and via	US-PGPU B; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 13:43
S5	90	("3661761" "4012307" "4123663" "4148705" "4216000" "4230553" "4264393" "4277321" "4278528" "4282077" "4285800" "4287851" "4289598" "4307283" "4384918" "4395323" "4508612" "4572759" "4632719" "4657619" "4817556" "4871433" "4897171" "4983253" "5055964" "5099571" "5113790" "5549041" "5603893" "6059935" "6103190").PN. OR ("2003/0091742" "2004/0157445" "4425210" "5258047" "5572398" "6248219" "6497839").URPN.	US-PGPU B; USPAT; USOCR	OR	OFF	2005/09/27 14:21
S6	90	S5 not S4	US-PGPU B; USPAT; USOCR	OR	OFF	2005/09/27 14:21
S4	55	S3 and (workpiece substrate wafer object) near (between interposed)	US-PGPU B; USPAT	OR	ON	2005/09/27 14:22
S7	239	S3 and (workpiece substrate wafer object) near (between interposed)	US-PGPU B; USPAT	OR	ON	2005/09/27 14:22

S8	69	S7 and ((atmospheric near pressure) "760" atm)	US-PGPU B; USPAT	OR	ON	2005/09/27 14:25
S9	320	S3 and (microelectrode electrode near array)	US-PGPU B; USPAT	OR	ON	2005/09/27 14:31
S10	17	S7 and S9	US-PGPU B; USPAT	OR	ON	2005/09/27 14:31
S11	13	(US-20040157445-\$ or US-20030091742-\$ or US-20050181606-\$ or US-20030170472-\$).did. or (US-6497839-\$ or US-6248219-\$ or US-5572398-\$ or US-5258047-\$ or US-4425210-\$ or US-6790341-\$ or US-5400209-\$ or US-5315473-\$ or US-5102523-\$).did.	US-PGPU B; USPAT	OR	OFF	2005/09/27 14:45
S12	4	S11 and (resistivity ohm)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2005/09/27 14:45

S13	296	(US-5413673-\$ or US-4978412-\$ or US-5549780-\$ or US-5665166-\$ or US-5705081-\$ or US-5795429-\$ or US-5911852-\$ or US-5938883-\$ or US-6136139-\$ or US-6136140-\$ or US-4313783-\$ or US-4631105-\$ or US-4799451-\$ or US-4829215-\$ or US-4931135-\$ or US-4987856-\$ or US-5015330-\$ or US-5203958-\$ or US-5221403-\$ or US-5252892-\$ or US-5255153-\$ or US-5334302-\$ or US-5342471-\$ or US-5342472-\$ or US-5387893-\$ or US-5411624-\$).did. or (US-5462629-\$ or US-5478429-\$ or US-5518572-\$ or US-5522934-\$ or US-5571366-\$ or US-5581874-\$ or US-5614025-\$ or US-5707692-\$ or US-5750987-\$ or US-5868849-\$ or US-5914568-\$ or US-5942075-\$ or US-5945008-\$ or US-5970907-\$ or US-5997962-\$ or US-6000360-\$ or US-6030667-\$ or US-6074518-\$ or US-6076483-\$ or US-6110287-\$ or US-6126779-\$ or US-6139682-\$ or US-6167835-\$ or US-6171662-\$ or	USPAT	OR	ON	2005/11/19 04:48
-----	-----	--	-------	----	----	---------------------

S3	1691	plasma and surface adj area near electrode	US-PGPU B; USPAT	OR	ON	2005/11/19 04:49
S14	1732	plasma and surface adj area near electrode	US-PGPU B; USPAT	OR	ON	2005/11/19 04:49
S15	3	S13 and S14	US-PGPU B; USPAT	OR	ON	2005/11/19 04:49
L7	12	(US-20030091742-\$ or US-20030170472-\$ or US-20040157445-\$).did. or (US-4425210-\$ or US-5102523-\$ or US-5258047-\$ or US-5315473-\$ or US-5400209-\$ or US-5572398-\$ or US-6248219-\$ or US-6497839-\$ or US-6790341-\$).did.	US-PGPU B; USPAT	OR	ON	2005/11/22 12:51
L9	1	7 and (microelectrode micro-electrode)	US-PGPU B; USPAT	OR	ON	2005/11/22 12:52
L11	0	7 and volumne adj RESISTIVITY	US-PGPU B; USPAT	OR	ON	2005/11/22 12:53
L10	3	7 and RESISTIVITY	US-PGPU B; USPAT	OR	ON	2005/11/22 12:54
L14	2	7 and (SF6 CF4 NF3 O2 Cl2 "SF.sub.6" "CF.sub.4" "NF. sub.3" "O.sub.2" "Cl.sub.2" HBr)	US-PGPU B; USPAT	OR	ON	2005/11/22 12:57
L13	6	7 and (inert ar argon he helium ne neon xe xenon)	US-PGPU B; USPAT	OR	ON	2005/11/22 12:58
L15	0	8 and 10 and 13	US-PGPU B; USPAT	OR	ON	2005/11/22 12:58
L16	1	8 and 13	US-PGPU B; USPAT	OR	ON	2005/11/22 12:58
L17	1	8 and 10	US-PGPU B; USPAT	OR	ON	2005/11/22 12:58
L18	0	13 and 10	US-PGPU B; USPAT	OR	ON	2005/11/22 12:58
L19	12	7 and plasma	US-PGPU B; USPAT	OR	ON	2005/11/22 13:00

L20	2	7 and volume adj RESISTIVITY and plasma	US-PGPU B; USPAT	OR	ON	2005/11/22 13:09
L12	2	7 and volume adj RESISTIVITY	US-PGPU B; USPAT	OR	ON	2005/11/22 13:12
L21	11	7 and (substrate wafer workpiece thin adj film)	US-PGPU B; USPAT	OR	ON	2005/11/22 13:12
L8	4	7 and array	US-PGPU B; USPAT	OR	ON	2005/11/22 13:43
L22	5	PCT/JP01/10666	US-PGPU B; USPAT	OR	ON	2005/11/22 13:43
L23	5	PCT/JP01/10666	US-PGPU B; USPAT; DERWEN T	OR	ON	2005/11/22 13:46
L24	0	PCT/JP01/10666	JPO; DERWEN T	OR	ON	2005/11/22 13:50
L25	4	"110666"	JPO; DERWEN T	OR	ON	2005/11/22 13:50
L26	3	"2001110666"	JPO; DERWEN T	OR	ON	2005/11/22 13:52
L27	0	WO near2 "2001" near2 "110666"	JPO; DERWEN T	OR	ON	2005/11/22 13:52
L28	0	WO near2 "110666"	JPO; DERWEN T	OR	ON	2005/11/22 13:52
L29	0	"2001" near2 "110666"	JPO; DERWEN T	OR	ON	2005/11/22 13:53
L30	0	"2001" near2 "10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:53
L31	0	WO near2 "10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:53

L32	3	"2001010666"	JPO; DERWEN T	OR	ON	2005/11/22 13:54
L33	1	"2001-010666"	JPO; DERWEN T	OR	ON	2005/11/22 13:54
L34	2	"10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:54
L36	0	35 and fukuda	JPO; DERWEN T	OR	ON	2005/11/22 13:55
L35	41	"0110666"	JPO; DERWEN T	OR	ON	2005/11/22 13:56
L37	0	"01-10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:56
L38	0	WO with "10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:56
L39	0	WO and "10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:56
L40	0	"2001" and "10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:57
L41	0	JP01 and "10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:57
L42	1	"01" and "10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:57
L43	0	"WO10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:57
L44	0	"WO0110666"	JPO; DERWEN T	OR	ON	2005/11/22 13:57

L45	0	"WO200110666"	JPO; DERWEN T	OR	ON	2005/11/22 13:58
L46	0	"WO2001-10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:58
L47	0	"WO-01-10666"	JPO; DERWEN T	OR	ON	2005/11/22 13:58
L48	7	cellulose adj ester with resistivity	JPO; DERWEN T	OR	ON	2005/11/22 14:16
L49	4	cellulose adj ester with resistivity	US-PGPU B; USPAT	OR	ON	2005/11/22 14:16